AUTOMATED TEST METHOD

ABSTRACT OF THE DISCLOSURE

An automated test method for performing a hi-pot test procedure for an electrical device through the use of a test program installed in a factory information system (FIS) and a test instrument connected to the FIS. The test program sends a control command to the test instrument that in turn executes the hi-pot test for the electrical device. Test results are obtained by the test program from the test instrument and sent to the FIS. The test results are stored in the FIS for future reference.

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